	Application No.	Applicant(s)	
Notice of Allowability	09/961,264 Examin r	OHKAWA, NARUMI Art Unit	<del> </del>
	Julio J. Maldonado	2823	
Th MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in this app or other appropriate communication IGHTS. This application is subject to	plication. If not include will be mailed in due	ed course. <b>THIS</b>
1. This communication is responsive to			
2. The allowed claim(s) is/are <u>1-4</u> .			
3. $\boxtimes$ The drawings filed on <u>25 September 2001</u> are accepted by	the Examiner.		
<ul> <li>4.  Acknowledgment is made of a claim for foreign priority ur</li> <li>a)  All b)  Some* c)  None of the:</li> <li>1.  Certified copies of the priority documents have</li> <li>2.  Certified copies of the priority documents have</li> <li>3.  Copies of the certified copies of the priority documents have</li> <li>International Bureau (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> </ul>	been received. been received in Application No		tion from th
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the rec	quirements
5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give			OTICE OF
6. CORRECTED DRAWINGS ( as "replacement sheets") mus	t be submitted.		
(a) ☐ including changes required by the Notice of Draftspers		948) attached	
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date			
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the C	Office action of	
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in t			back) of
7. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT			Note the
Attachm nt(s)  1. ☑ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date	_	(PTO-413), te <u>20040623</u> nent/Comment	,
Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. ⊠ Examiner's Stateme 9. □ Other	ent of Reasons for Allo	wance

## **DETAILED ACTION**

## **EXAMINER'S AMENDMENT**

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Sadao Kinashi (Reg. No. 48,075) on 06/23/2004.

The application has been amended as follows: Claims 5-15 are cancelled.

## Allowable Subject Matter

- 2. Claims 1-4 are allowed.
- 3. The following is an examiner's statement of reasons for allowance:

The prior art of record, Ueno et al. to 6,492,690 B2 teach in Figs.33-41 and related text a method of manufacturing a semiconductor device including preparing a semiconductor substrate (51) having a memory cell area and a logic area; forming a gate insulating film (53) on the substrate (51); forming a silicon film (550) on the gate insulating film (53); doping impurities into the silicon film (550) such that the concentration of said impurities in said logic area is higher than the concentration of said impurities in said logic area is higher than the concentration of said impurities in said memory cell area; patterning the silicon film (550); and forming source and drain regions (156) (column 44, line 55 – column 48, line 60). However, Ueno et al. teach away from doping impurities in a silicon film to make a region of the silicon film in the memory cell area having a first impurity concentration and to make a

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region of the silicon film in the logic cell area having a second impurity concentration

lower than the first impurity concentration.

Any comments considered necessary by applicant must be submitted no later

than the payment of the issue fee and, to avoid processing delays, should preferably

accompany the issue fee. Such submissions should be clearly labeled "Comments on

Statement of Reasons for Allowance."

Conclusion

4. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to examiner Julio J. Maldonado whose telephone number

is (571) 272-1864. The examiner can normally be reached on Monday through Friday.

5. If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Olik Chaudhuri, can be reached on (571) 272-1855. The fax number for this

group is 703-872-9306 for before final submissions, 703-872-9306 for after final

submissions and the customer service number for group 2800 is (703) 306-3329.

Updates can be found at http://www.uspto.gov/web/info/2800.htm.

Julio J. Maldonado Patent Examiner Art Unit 2823

Julio J. Maldonado June 24, 2004

George Fourson
Primary Examiner